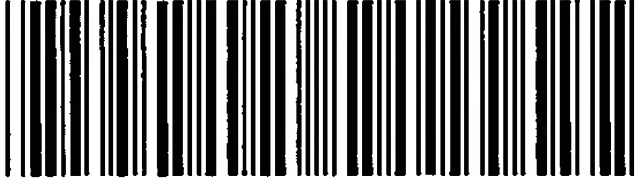


<b>Search Notes</b>  	<b>Application/Control No.</b>  10630984	<b>Applicant(s)/Patent Under Reexamination</b>  KAKUMOTO ET AL.
	<b>Examiner</b>  Henn, Timothy J	<b>Art Unit</b>  2622

SEARCHED			
Class	Subclass	Date	Examiner
348	241,243,245,296,301,308	10/28/06	TJH
348	300	6/22/07	TJH

SEARCH NOTES		
Search Notes	Date	Examiner
Updated Search	6/22/07	TJH
Consulted Vivek Srivastava -> see Lin Ye, NgocYen Vu	6/22/07	TJH
Consulted NgocYen Vu	6/22/07	TJH
Consulted Lin Ye -> Correlated Double Sampling (CDS), Tapered Reset	6/22/07	TJH
Consulted Vivek Srivastava Re: CDS and reset voltages	6/22/07	TJH

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
348	301,308	6/22/07	TJH